Application/Control No. Applicant(s)/Patent Under Reexamination 09/753,245 BAEK ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2153 Krisna Lim **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 11-2004 711/114 US-6,820,171 Weber et al. US-В US-С US-D US-Ε F US-US-G US-Н US-US-J Κ US-US-L US-**FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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